

International IOR Rectifier

IRS2111(S)PbF

HALF-BRIDGE DRIVER

Features

- Floating channel designed for bootstrap operation
- Fully operational to +600 V
- Tolerant to negative transient voltage, dV/dt immune
- Gate drive supply range from 10 V to 20 V
- Undervoltage lockout for both channels
- CMOS Schmitt-triggered inputs with pull-down
- Matched propagation delay for both channels
- Internally set deadtime
- High side output in phase with input

Product Summary

| | |
|----------------------------|-----------------|
| V_{OFFSET} | 600 V max. |
| $I_{\text{O}+/-}$ | 200 mA / 420 mA |
| V_{OUT} | 10 V - 20 V |
| $t_{\text{on/off}}$ (typ.) | 750 ns & 150 ns |
| Deadtime (typ.) | 650 ns |

Description

The IRS2111 is a high voltage, high speed power MOSFET and IGBT driver with dependent high and low side referenced output channels designed for half-bridge applications. Proprietary HVIC and latch immune CMOS technologies enable ruggedized monolithic construction. Logic input is compatible with standard CMOS outputs. The output drivers feature a high pulse current buffer stage designed for minimum driver cross-conduction. Internal deadtime is provided to avoid shoot-through in the output half-bridge. The floating channel can be used to drive an N-channel power MOSFET or IGBT in the high side configuration which operates up to 600 V.

Packages

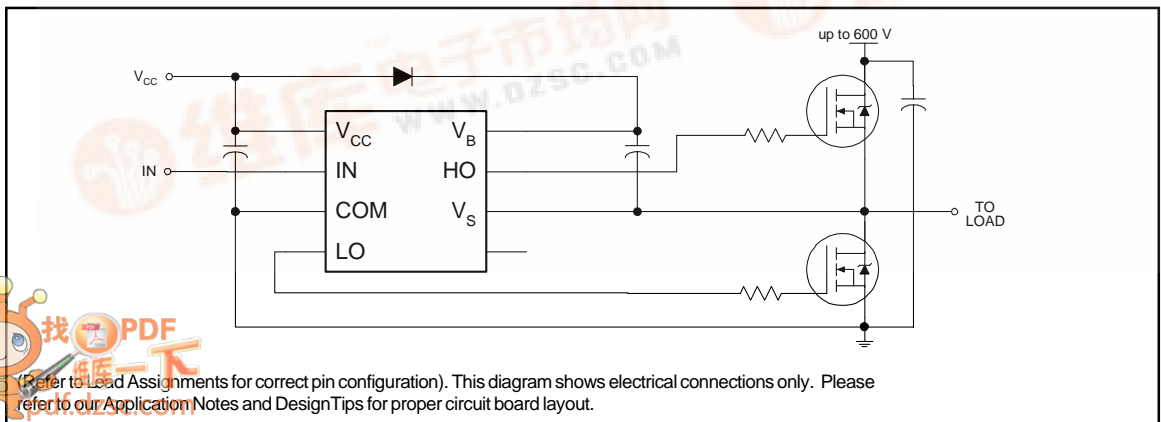


8-Lead PDIP
IRS2111PbF



8-Lead SOIC
IRS2111SPbF

Typical Connection



Absolute Maximum Ratings

Absolute maximum ratings indicate sustained limits beyond which damage to the device may occur. All voltage parameters are absolute voltages referenced to COM. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Additional information is shown in Figs. 7 through 10.

| Symbol | Definition | Min. | Max. | Un | |
|---------------------|--|----------------------|-----------------------|-------|-----|
| V _B | High side floating supply voltage | -0.3 | 625 (Note 1) | | |
| V _S | High side floating supply offset voltage | V _B - 25 | V _B + 0.3 | | |
| V _{HO} | High side floating output voltage | V _S - 0.3 | V _B + 0.3 | | |
| V _{CC} | Low side and logic fixed supply voltage | -0.3 | 25 (Note 1) | V | |
| V _{LO} | Low side output voltage | -0.3 | V _{CC} + 0.3 | | |
| V _{IN} | Logic input voltage | -0.3 | V _{CC} + 0.3 | | |
| dV _S /dt | Allowable offset supply voltage transient (Fig. 2) | — | 50 | V/ | |
| P _D | Package power dissipation @ T _A ≤ +25°C | (8 Lead PDIP) | — | 1.0 | W |
| | | (8 lead SOIC) | — | 0.625 | |
| R _{thJA} | Thermal resistance, junction to ambient | (8 lead PDIP) | — | 125 | °C/ |
| | | (8 lead SOIC) | — | 200 | |
| T _J | Junction temperature | — | 150 | | |
| T _S | Storage temperature | -55 | 150 | °C | |
| T _L | Lead temperature (soldering, 10 seconds) | — | 300 | | |

Note 1: All supplies are fully tested at 25 V, and an internal 20 V clamp exists for each supply

Recommended Operating Conditions

The input/output logic timing diagram is shown in Fig. 1. For proper operation the device should be used within the recommended conditions. The V_S offset rating is tested with all supplies biased at a 15 V differential.

| Symbol | Definition | Min. | Max. | Un |
|-----------------|--|---------------------|---------------------|----|
| V _B | High side floating supply absolute voltage | V _S + 10 | V _S + 20 | |
| V _S | High side floating supply offset voltage | Note 2 | 600 | |
| V _{HO} | High side floating output voltage | V _S | V _B | |
| V _{CC} | Low side and logic fixed supply voltage | 10 | 20 | V |
| V _{LO} | Low side output voltage | 0 | V _{CC} | |
| V _{IN} | Logic input voltage | 0 | V _{CC} | |
| T _A | Ambient temperature | -40 | 125 | °C |

Note 2: Logic operational for V_S of -5 V to +600 V. Logic state held for V_S of -5 V to -V_{BS}. (Please refer to the Design DT97-3 for more details).

Dynamic Electrical Characteristics

V_{BIAS} (V_{CC} , V_{BS}) = 15 V, C_L = 1000 pF and T_A = 25 °C unless otherwise specified. The dynamic electrical characteristics are measured using the test circuit shown in Fig. 3.

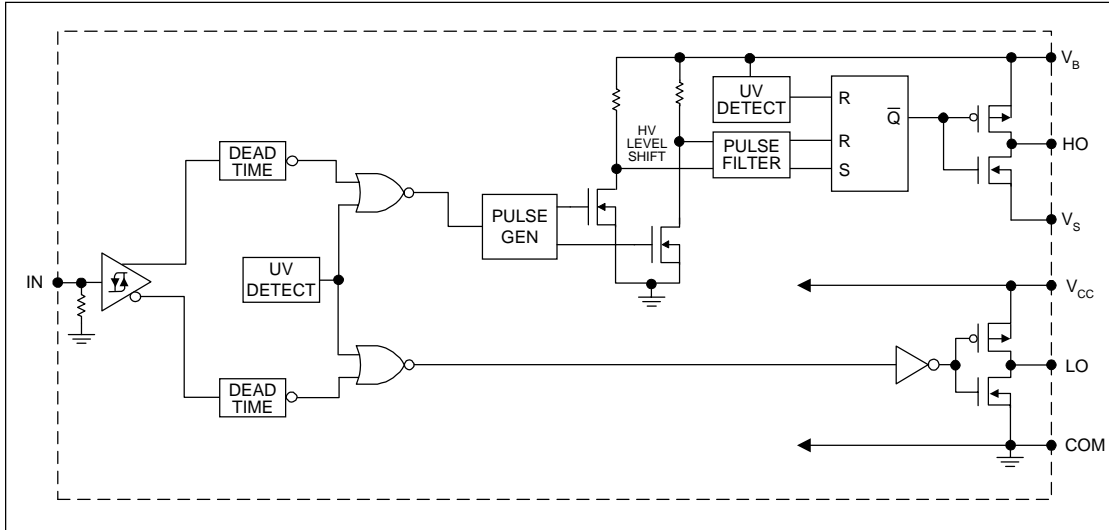
| Symbol | Definition | Min. | Typ. | Max. | Units | Test Conditions |
|-----------|---|------|------|------|-------|-----------------|
| t_{on} | Turn-on propagation delay | 550 | 750 | 950 | ns | $V_S = 0$ V |
| t_{off} | Turn-off propagation delay | — | 150 | 180 | | $V_S = 600$ V |
| t_r | Turn-on rise time | — | 75 | 130 | | |
| t_f | Turn-off fall time | — | 35 | 65 | | |
| DT | Deadtime, LS turn-off to HS turn-on & HS turn-off to LS turn-on | 480 | 650 | 820 | | |
| MT | Delay matching, HS & LS turn-on/off | — | 30 | — | | |

Static Electrical Characteristics

V_{BIAS} (V_{CC} , V_{BS}) = 15 V and T_A = 25 °C unless otherwise specified. The V_{IN} , V_{TH} , and I_{IN} parameters are referenced to COM. The V_O and I_O parameters are referenced to COM and are applicable to the respective output leads: HO or LO.

| Symbol | Definition | Min. | Typ. | Max. | Units | Test Conditions |
|-------------|---|------|------|------|---------|--|
| V_{IH} | Logic "1" input voltage for HO & logic "0" for LO | 6.4 | — | — | V | $V_{CC} = 10$ V |
| | | 9.5 | — | — | | $V_{CC} = 15$ V |
| | | 12.6 | — | — | | $V_{CC} = 20$ V |
| V_{IL} | Logic "0" input voltage for HO & logic "1" for LO | — | — | 3.8 | | $V_{CC} = 10$ V |
| | | — | — | 6.0 | | $V_{CC} = 15$ V |
| | | — | — | 8.3 | | $V_{CC} = 20$ V |
| V_{OH} | High level output voltage, $V_{BIAS} - V_O$ | — | 0.05 | 0.2 | mV | $I_O = 2$ mA |
| V_{OL} | Low level output voltage, V_O | — | 0.02 | 0.1 | | |
| I_{LK} | Offset supply leakage current | — | — | 50 | μ A | $V_B = V_S = 600$ V |
| I_{QBS} | Quiescent V_{BS} supply current | — | 50 | 100 | | $V_{IN} = 0$ V or V_{CC} |
| I_{QCC} | Quiescent V_{CC} supply current | — | 70 | 180 | | $V_{IN} = V_{CC}$ |
| I_{IN+} | Logic "1" input bias current | — | 30 | 50 | | $V_{IN} = 0$ V |
| I_{IN-} | Logic "0" input bias current | — | — | 1.0 | | |
| V_{BSUV+} | V_{BS} supply undervoltage positive going threshold | 7.6 | 8.6 | 9.6 | V | |
| V_{BSUV-} | V_{BS} supply undervoltage negative going threshold | 7.2 | 8.2 | 9.2 | | |
| V_{CCUV+} | V_{CC} supply undervoltage positive going threshold | 7.6 | 8.6 | 9.6 | | |
| V_{CCUV-} | V_{CC} supply undervoltage negative going threshold | 7.2 | 8.2 | 9.2 | | |
| I_{O+} | Output high short circuit pulsed current | 200 | 290 | — | mA | $V_O = 0$ V, $V_{IN} = V_{CC}$ $PW \leq 10$ μ s |
| I_{O-} | Output low short circuit pulsed current | 420 | 600 | — | | $V_O = 15$ V, $V_{IN} = 0$ V $PW \leq 10$ μ s |

Functional Block Diagram



Lead Definitions

| Symbol | Description |
|-----------------|--|
| IN | Logic input for high side and low side gate driver outputs (HO & LO), in phase with HO |
| V _B | High side floating supply |
| HO | High side gate drive output |
| V _S | High side floating supply return |
| V _{CC} | Low side and logic fixed supply |
| LO | Low side gate drive output |
| COM | Low side return |

Lead Assignments

| | |
|--------------------|--------------------|
| <p>8 Lead DIP</p> | <p>8 Lead SOIC</p> |
| IRS2111 | IRS2111S |
| Part Number | |

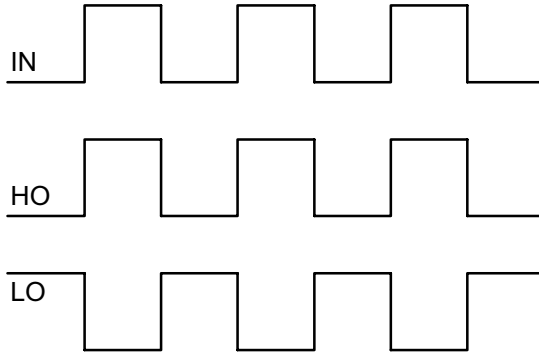


Figure 1. Input/Output Timing Diagram

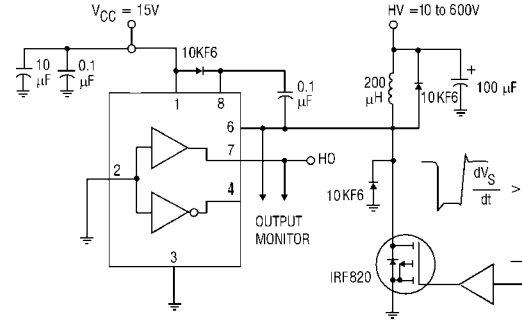


Figure 2. Floating Supply Voltage Transient Test Circuit

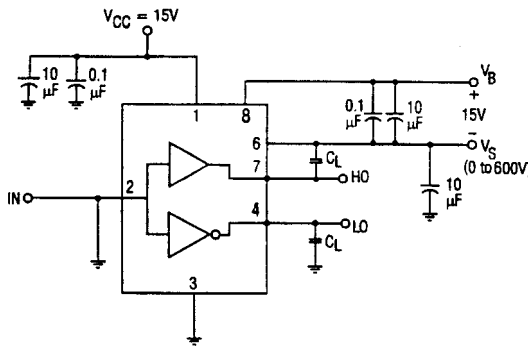


Figure 3. Switching Time Test Circuit

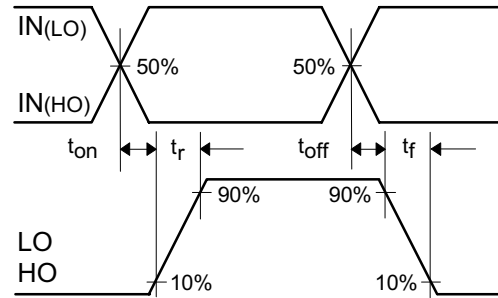


Figure 4. Switching Time Waveform Definition

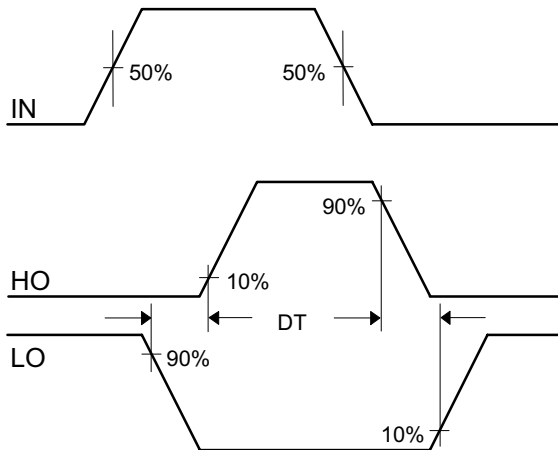


Figure 5. Deadtime Waveform Definitions

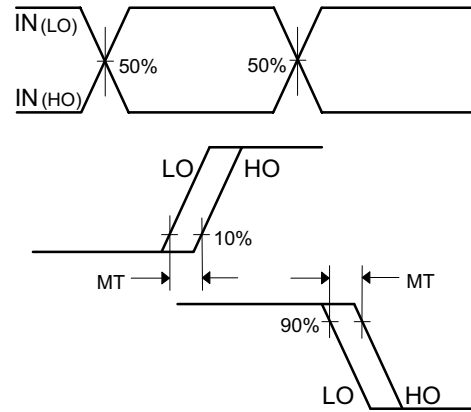


Figure 6. Delay Matching Waveform Definitions

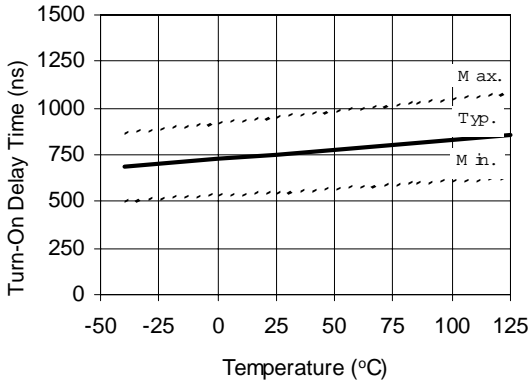


Figure 7A Turn-On Time vs Temperature

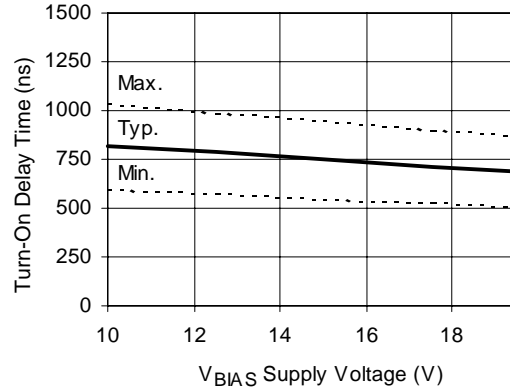


Figure 7B Turn-On Time vs Voltage

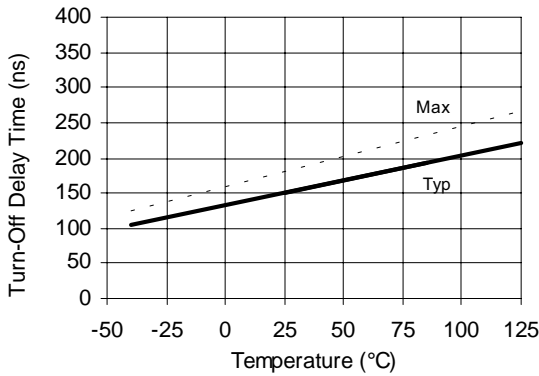


Figure 8A Turn-Off Time vs Temperature

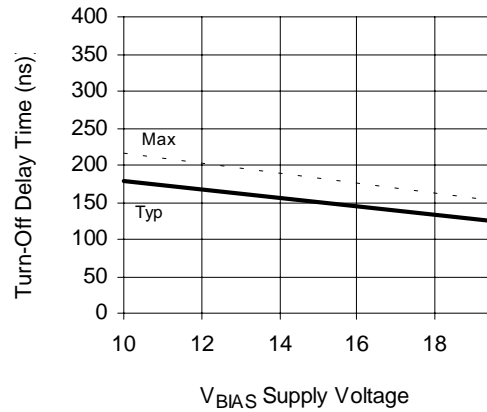


Figure 8B Turn-Off Time vs Voltage

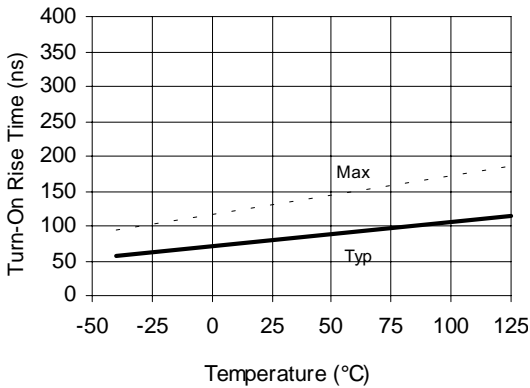


Figure 9A Turn-On Rise Time vs Temperature

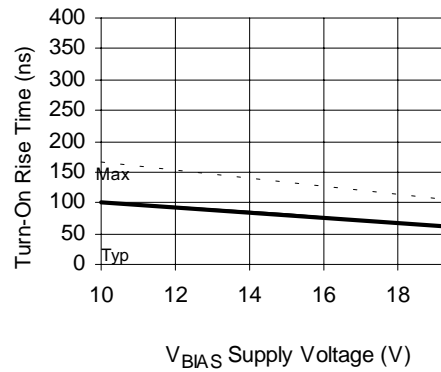


Figure 9B Turn-On Rise Time vs Voltage

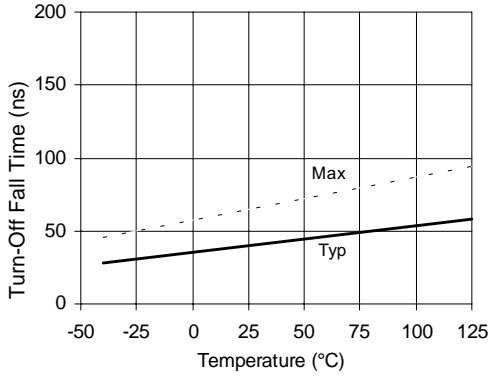


Figure 10A Turn-Off Fall Time vs Temperature

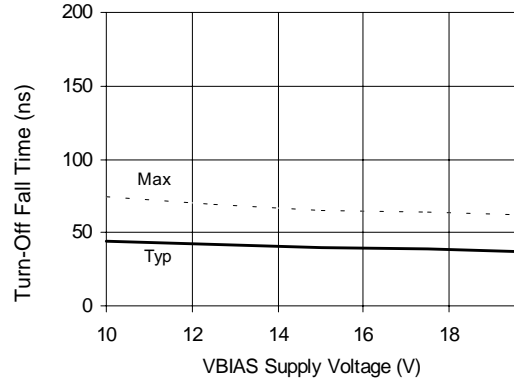


Figure 10B Turn-Off Fall Time vs Voltage

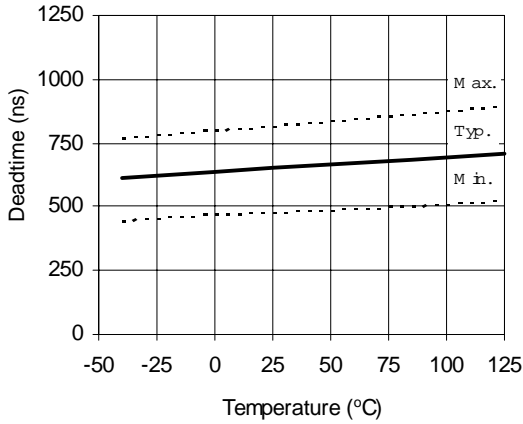


Figure 11A Deadtime vs Temperature

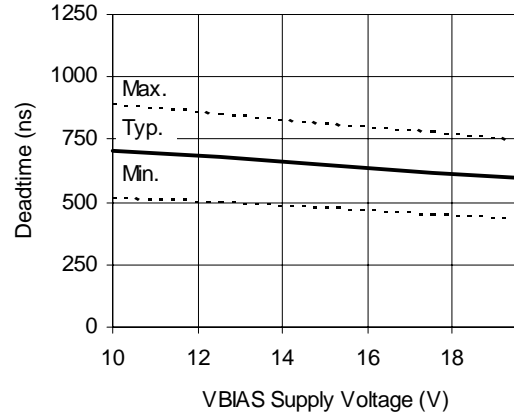


Figure 11B Deadtime vs Voltage

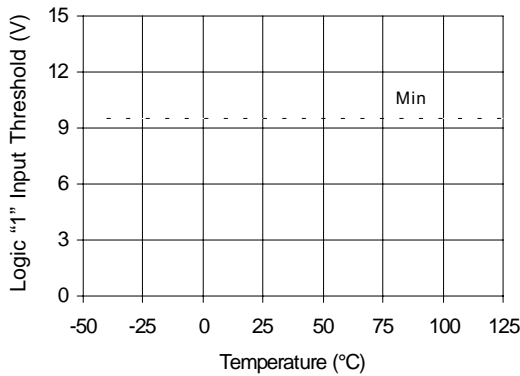


Figure 12A Logic "1" Input voltage for HO & Logic "0" for LO vs Temperature

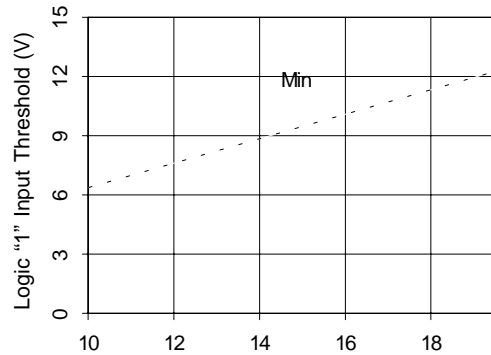


Figure 12B Logic "1" Input voltage for HO & Logic "0" for LO vs Voltage

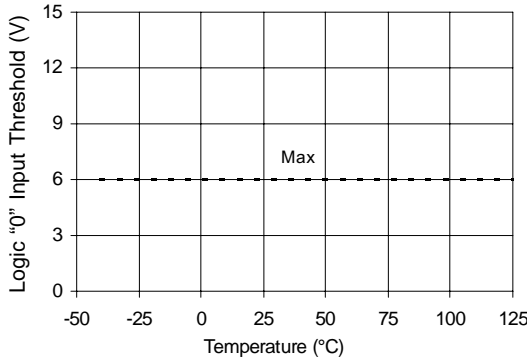


Figure 13A Logic "0" Input voltage for HO & Logic "1" for LO vs Temperature

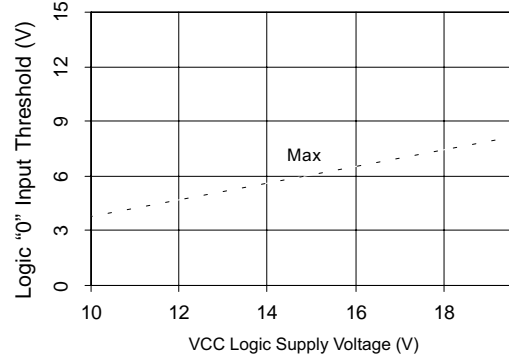


Figure 13B Logic "0" Input voltage for HO & Logic "1" for LO vs Voltage

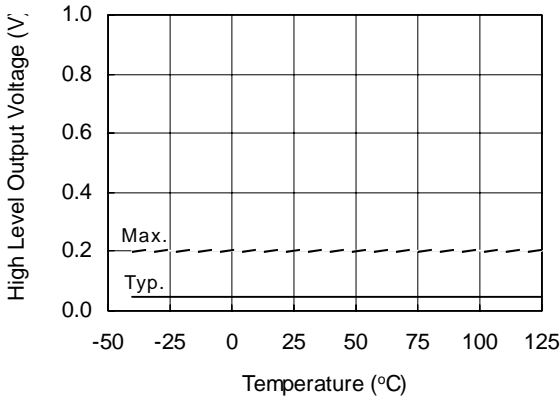


Figure 14A. High Level Output vs. Temperature

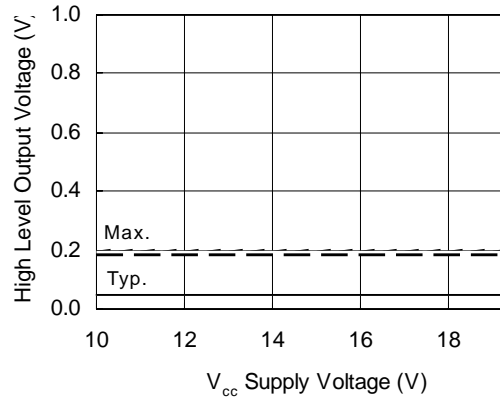


Figure 14B. High Level Output vs. Supply Voltage

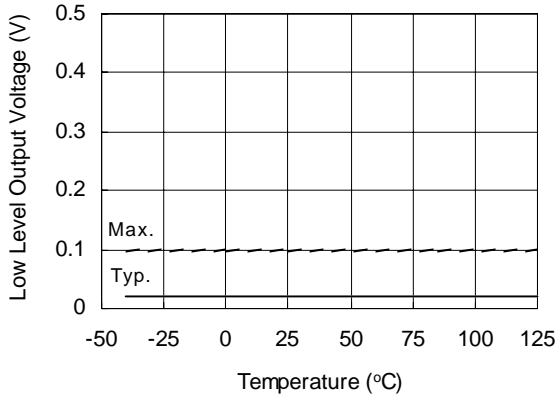


Figure 15A. Low Level Output vs. Temperature

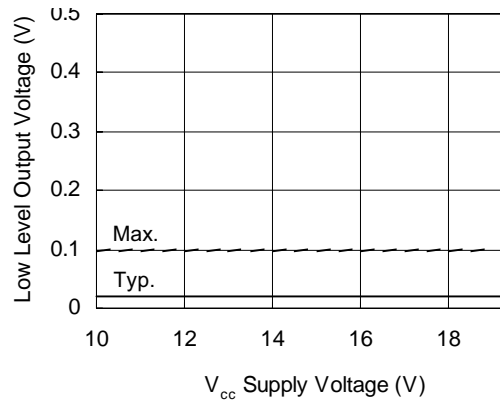


Figure 15B. Low Level Output vs. Voltage

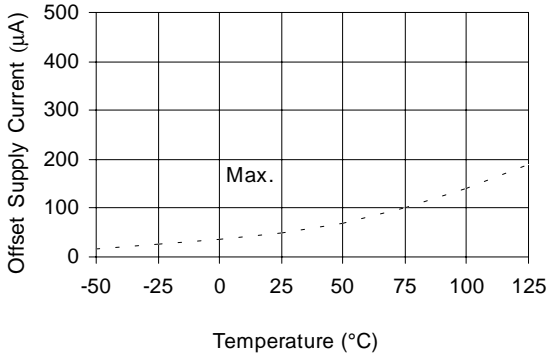


Figure 16A Offset Supply Current vs Temperature

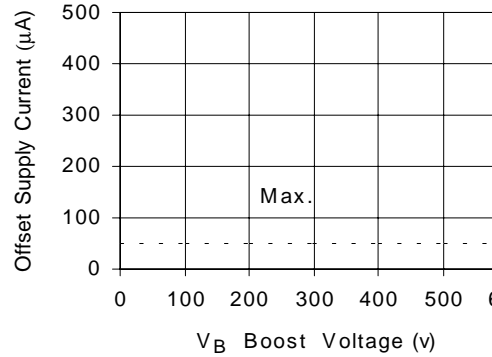


Figure 16B Offset Supply Current vs V_B Boost Voltage

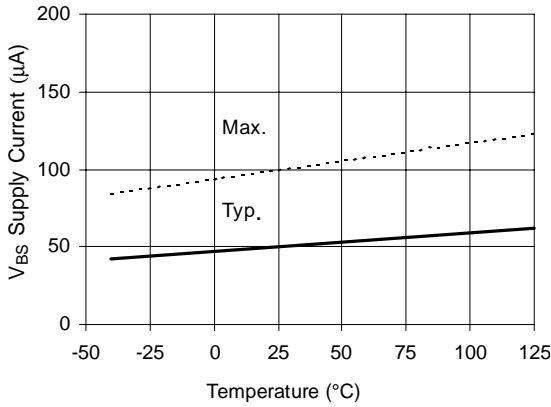


Figure 17A V_{BS} Supply Current vs Temperature

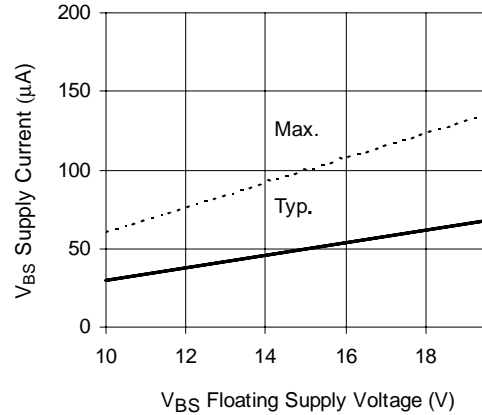


Figure 17B V_{BS} Supply Current vs V_{BS} Floating Supply Voltage

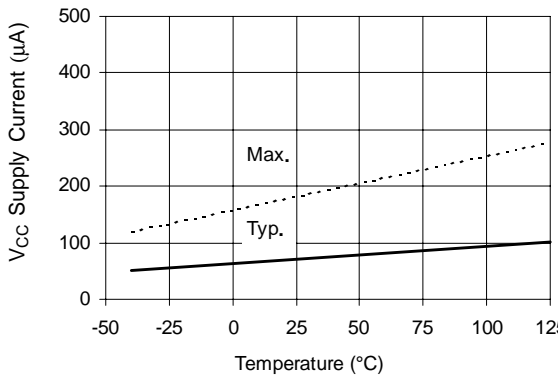


Figure 18A V_{CC} Supply Current vs Temperature

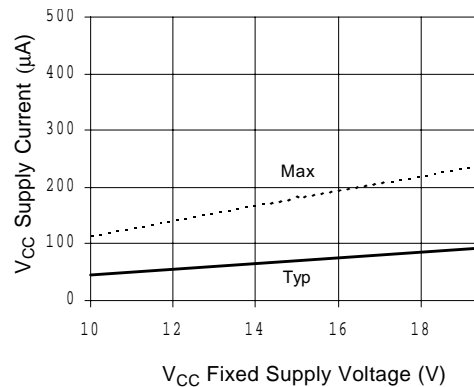


Figure 18B V_{CC} Supply Current vs V_{CC} Fixed Supply Voltage

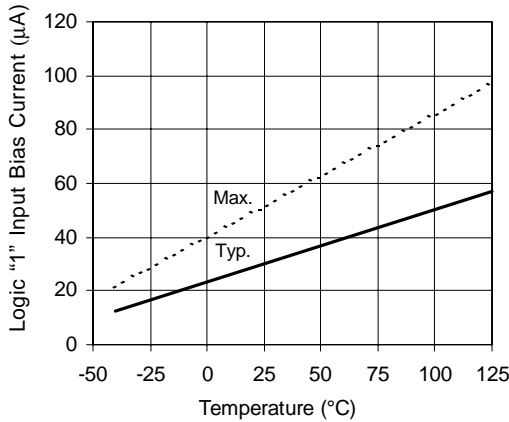


Figure 19A Logic "1" Input Current vs. Temperature

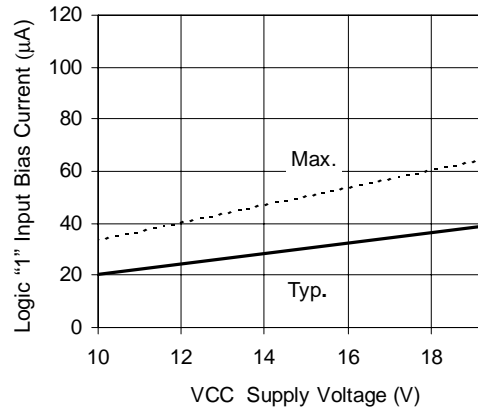


Figure 19B Logic "1" Input Current vs. VCC Voltage

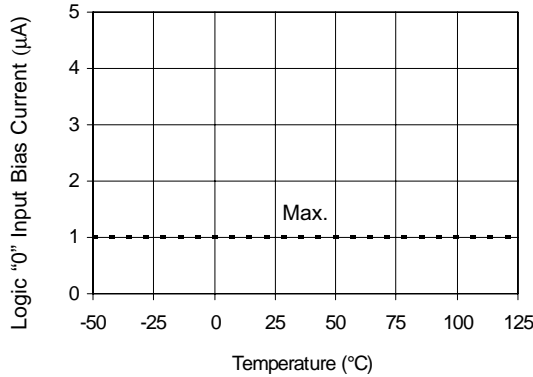


Figure 20A. Logic "0" Input Current vs. Temperature

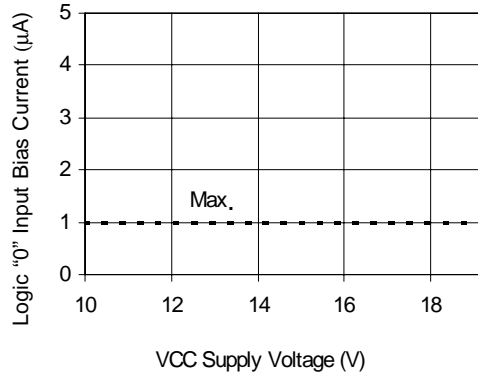


Figure 20B. Logic "0" Input Current vs. VCC Voltage

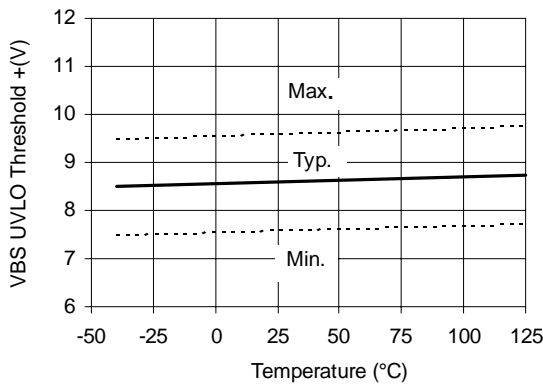


Figure 21 V_{BS} Undervoltage Threshold (+) vs. Temperature

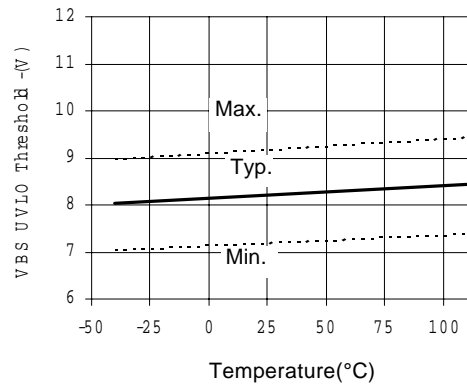


Figure 22 V_{BS} Undervoltage Threshold (-) vs. Temperature

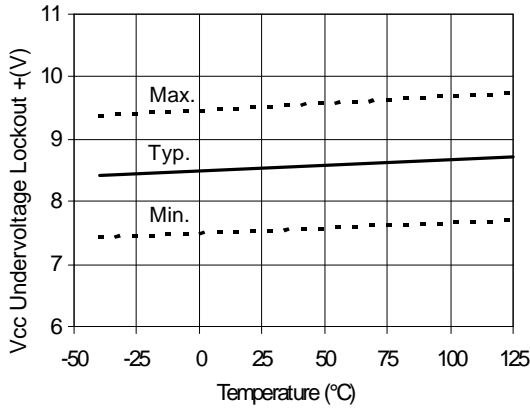


Figure 23 V_{CC} Undervoltage (-) vs Temperature

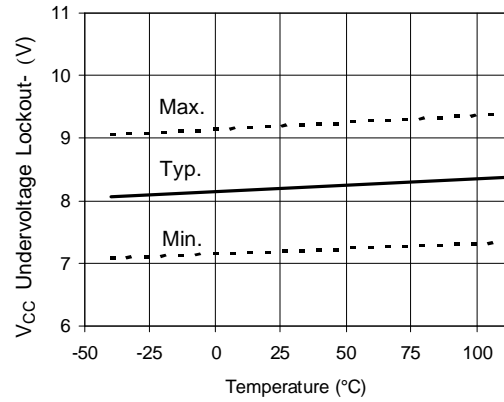


Figure 24 V_{CC} Undervoltage (-) vs Temperature

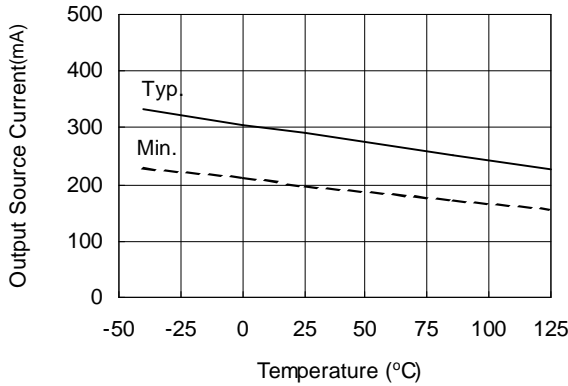


Figure 25A Output Source Current vs Temperature

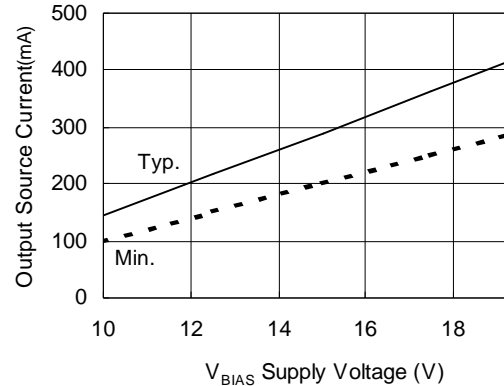


Figure 25B Output Source Current vs V_{BIAS} Supply Voltage

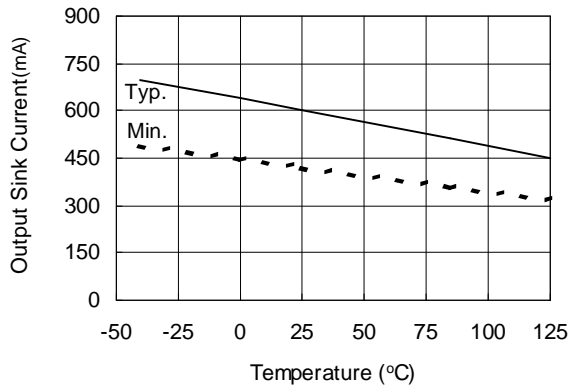


Figure 26A Output Sink Current vs Temperature

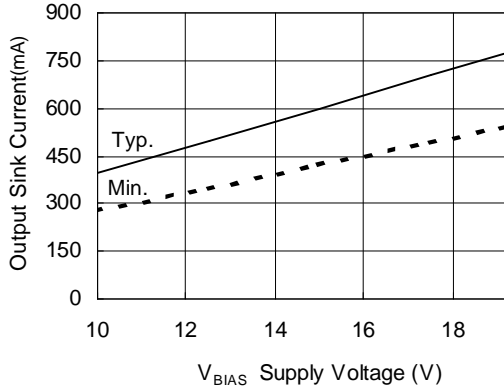


Figure 26B Output Sink Current vs V_{BIAS} Supply Voltage

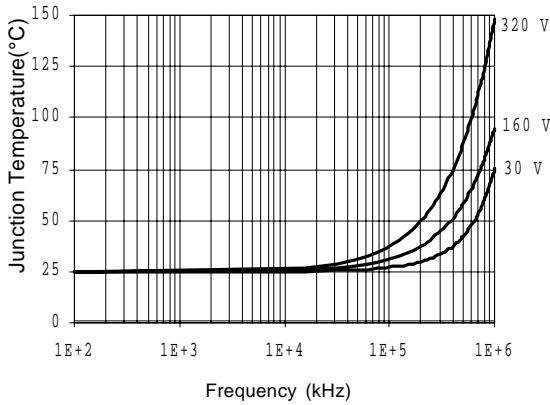


Figure 27. IR2111 T_J vs. Frequency (IRFBC20)
 R_{GATE} = 33 Ω, V_{CC} = 15 V

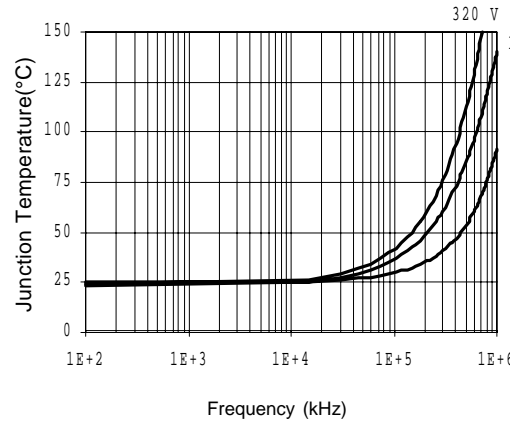


Figure 28. IR2111 T_J vs. Frequency (IRFBC30)
 R_{GATE} = 22 Ω, V_{CC} = 15 V

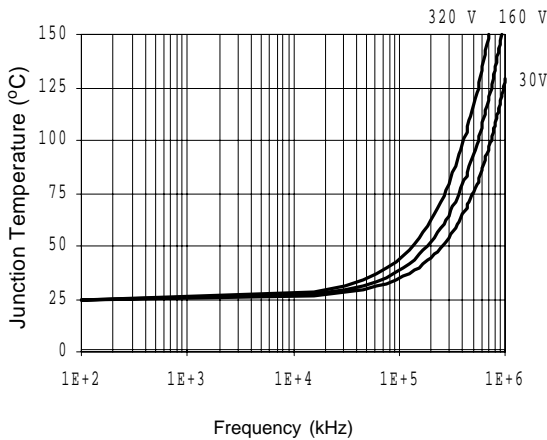


Figure 29. IR2111 T_J vs. Frequency (IRFBC40)
 R_{GATE} = 15 Ω, V_{CC} = 15 V

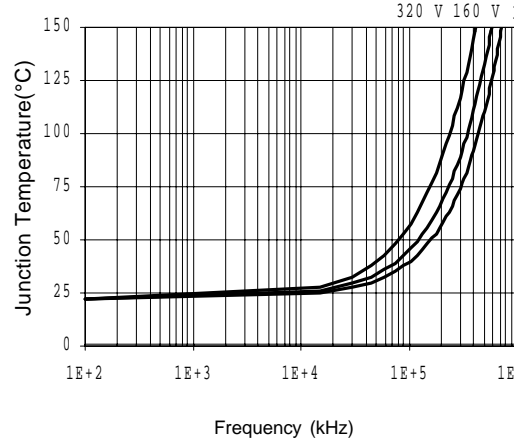


Figure 30. IR2111 T_J vs. Frequency (IRFPC50)
 R_{GATE} = 10 Ω, V_{CC} = 15 V

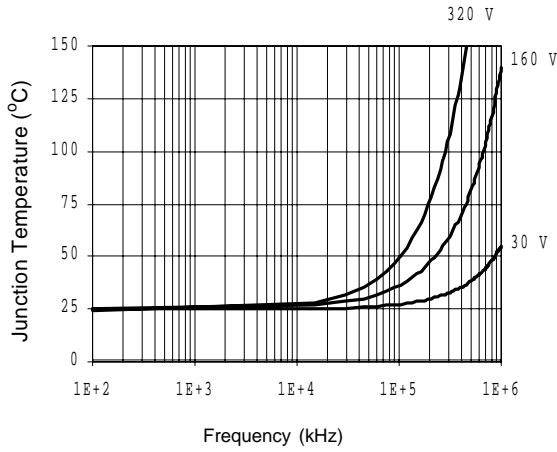


Figure 31. IR2111S T_J vs. Frequency (IRFBC20)
R_{GATE} = 33 Ω, V_{CC} = 15 V

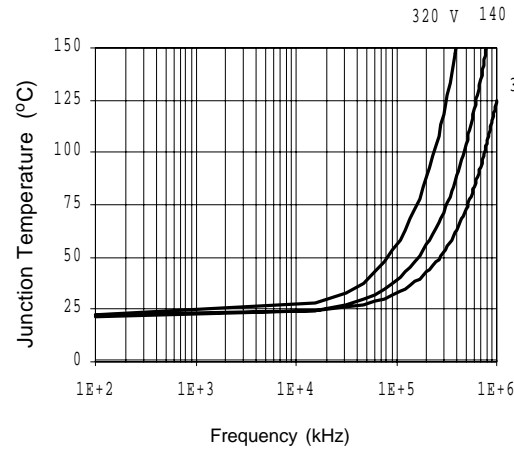


Figure 32. IR2111S T_J vs. Frequency (IRFBC30)
R_{GATE} = 22 Ω, V_{CC} = 15 V

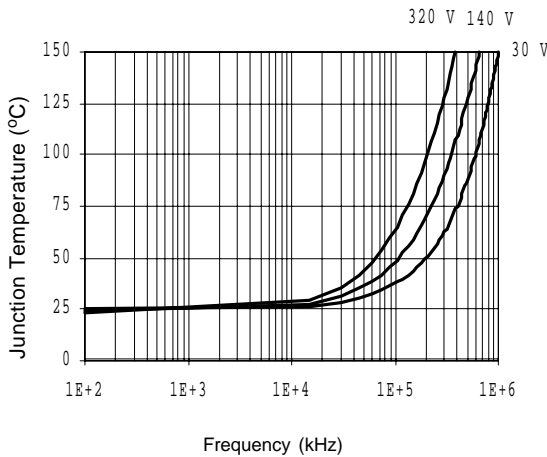


Figure 33. IR2111S T_J vs. Frequency (IRFBC40)
R_{GATE} = 15 Ω, V_{CC} = 15 V

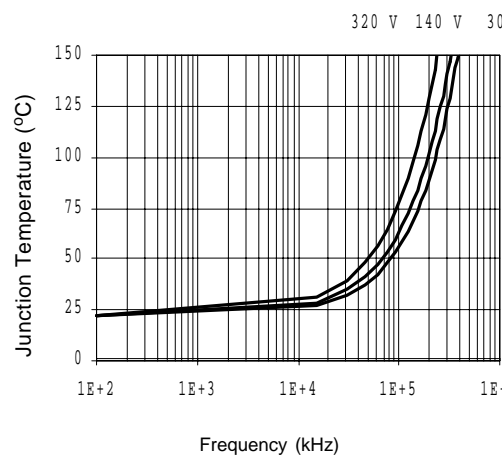
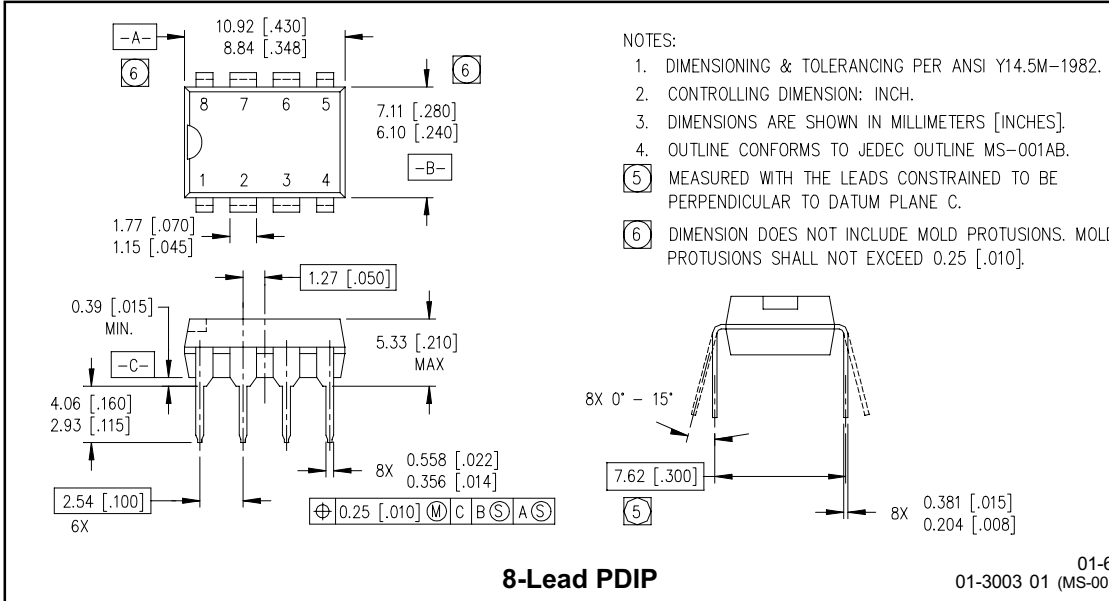
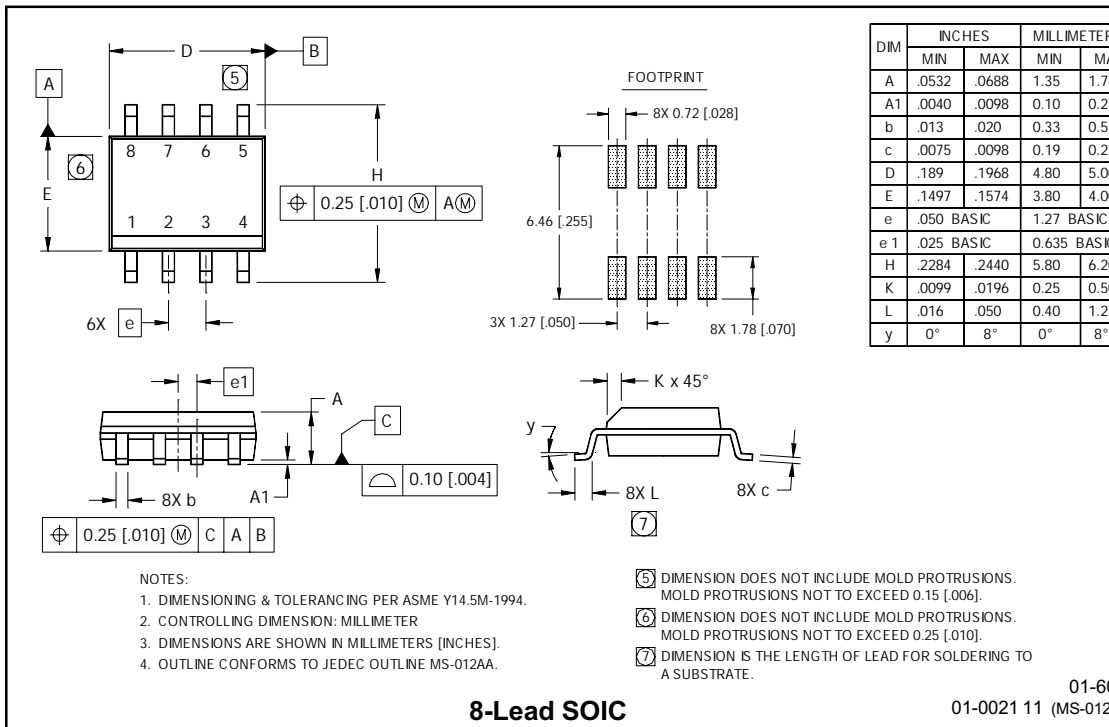


Figure 34. IR2111S T_J vs. Frequency (IRFPC50)
R_{GATE} = 10 Ω, V_{CC} = 15 V

Case outlines

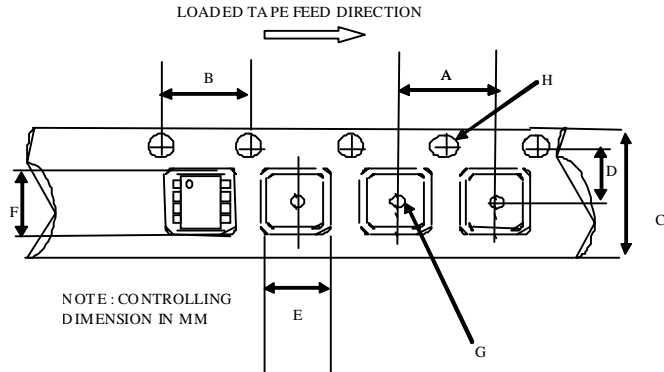


01-6
01-3003 01 (MS-001)



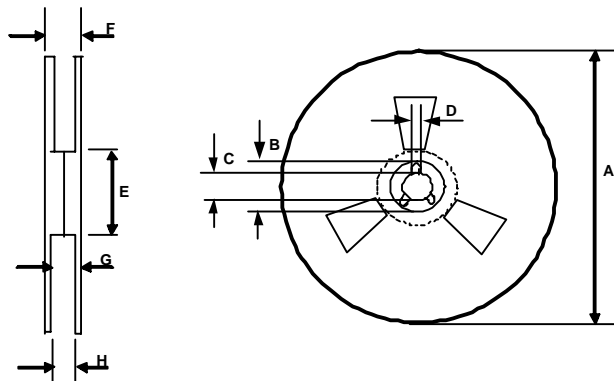
01-6
01-0021 11 (MS-012)

**Tape & Reel
8-lead SOIC**



CARRIER TAPE DIMENSION FOR 8SOICN

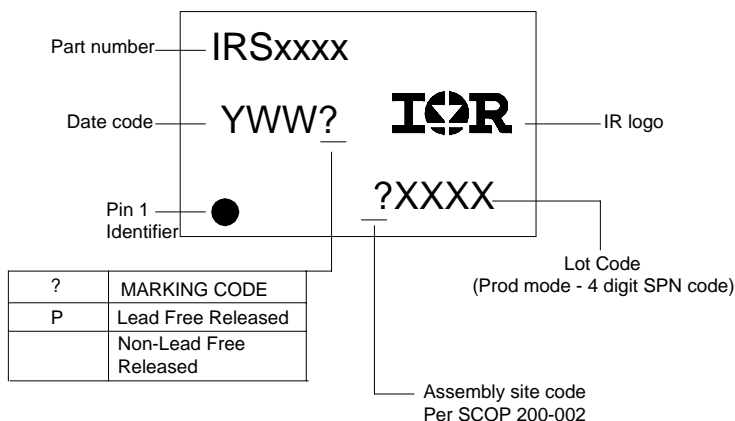
| Code | Metric | | Imperial | |
|------|--------|-------|----------|-------|
| | Min | Max | Min | Max |
| A | 7.90 | 8.10 | 0.311 | 0.318 |
| B | 3.90 | 4.10 | 0.153 | 0.161 |
| C | 11.70 | 12.30 | 0.46 | 0.484 |
| D | 5.45 | 5.55 | 0.214 | 0.218 |
| E | 6.30 | 6.50 | 0.248 | 0.255 |
| F | 5.10 | 5.30 | 0.200 | 0.208 |
| G | 1.50 | n/a | 0.059 | n/a |
| H | 1.50 | 1.60 | 0.059 | 0.062 |



REEL DIMENSIONS FOR 8SOICN

| Code | Metric | | Imperial | |
|------|--------|--------|----------|--------|
| | Min | Max | Min | Max |
| A | 329.60 | 330.25 | 12.976 | 13.001 |
| B | 20.95 | 21.45 | 0.824 | 0.844 |
| C | 12.80 | 13.20 | 0.503 | 0.519 |
| D | 1.95 | 2.45 | 0.767 | 0.096 |
| E | 98.00 | 102.00 | 3.858 | 4.015 |
| F | n/a | 18.40 | n/a | 0.724 |
| G | 14.50 | 17.10 | 0.570 | 0.673 |
| H | 12.40 | 14.40 | 0.488 | 0.566 |

LEADFREE PART MARKING INFORMATION



ORDER INFORMATION

8-Lead PDIP IRS2111PbF
 8-Lead SOIC IRS2111SPbF
 8-Lead SOIC Tape & Reel IRS2111STRPbF